Unit: mm

TOSHIBA Field Effect Transistor Silicon N Channel MOS Type (L^2 - π -MOSV)

2SK2313

Chopper Regulator, DC-DC Converter and Motor Drive Applications

• 4 V gate drive

• Low drain–source ON resistance $: R_{DS}(ON) = 8 \text{ m}\Omega \text{ (typ.)}$

• High forward transfer admittance $: |Y_{fs}| = 60 \text{ S (typ.)}$

• Low leakage current : $I_{DSS} = 100 \mu A \text{ (max) (V}_{DS} = 60 \text{ V)}$

• Enhancement-mode : $V_{th} = 0.8 \sim 2.0 \text{ V (V}_{DS} = 10 \text{ V, I}_{D} = 1 \text{ mA})$

Maximum Ratings (Ta = 25°C)

Characteristics		Symbol	Rating	Unit	
Drain-source voltage		V_{DSS}	60	V	
Drain-gate voltage (R _{GS} = 20 kΩ)		V_{DGR}	60	V	
Gate-source voltage		V _{GSS}	±20	V	
Drain current	DC (Note 1)	I _D	60	Α	
	Pulse (Note 1)	I_{DP}	240	Α	
Drain power dissipatio	n (Tc = 25°C)	P_{D}	150	W	
Single pulse avalanche energy (Note 2)		E _{AS}	1054	mJ	
Avalanche current		I _{AR}	60	Α	
Repetitive avalanche energy (Note 3)		E _{AR}	15	mJ	
Channel temperature		T _{ch}	150	°C	
Storage temperature range		T _{stg}	-55~150	°C	

Weight: 4.6 g (typ.)

Thermal Characteristics

Characteristics	Symbol	Max	Unit
Thermal resistance, channel to case	R _{th (ch-c)}	0.833	°C/W
Thermal resistance, channel to ambient	R _{th (ch-a)}	50	°C/W

Note 1: Please use devices on condition that the channel temperature is below 150°C.

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Note 2: V_{DD} = 25 V, T_{ch} = 25°C (initial), L = 398 μ H, R_G = 25 Ω , I_{AR} = 60 A

Note 3: Repetitive rating: Pulse width limited by maximum channel temperature

This transistor is an electrostatic sensitive device.

Please handle with caution.



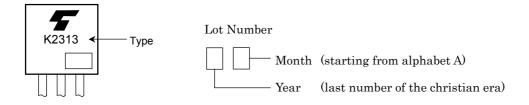
Electrical Characteristics (Ta = 25°C)

Charac	eteristics	Symbol	Test Condition	Min	Тур.	Max	Unit	
Gate leakage cu	rrent	I _{GSS}	V _{GS} = ±16 V, V _{DS} = 0 V	_	_	±10	μΑ	
Drain cut-off cui	rrent	I _{DSS}	V _{DS} = 60 V, V _{GS} = 0 V	1	_	100	μA	
Drain-source br	eakdown voltage	V _{(BR) DSS}	I _D = 10 mA, V _{GS} = 0 V	60		_	V	
Gate threshold v	oltage	V_{th}	V _{DS} = 10 V, I _D = 1 mA	0.8	_	2.0	٧	
Drain course ON registers		D	V _{GS} = 4 V, I _D = 30 A	_	12	15	mΩ	
Drain-source ON resistance	N resistance	R _{DS} (ON)	V _{GS} = 10 V, I _D = 30 A	_	8	11	11177	
Forward transfer	admittance	Y _{fs}	V _{DS} = 10 V, I _D = 30 A	40	60	_	S	
Input capacitano	e	C _{iss}		_	5400	_		
Reverse transfer capacitance		C _{rss}		_	920	_	pF	
Output capacitance		C _{oss}		_	2600	_		
Switching time	Rise time	t _r	V _{GS} _{0V}	_	30	_		
	Turn-on time	t _{on}		_	60	_	- ns	
	Fall time	t _f		_	65	_		
	Turn-off time	t _{off}	$V_{DD} = 30V$ Duty $\leq 1\%$, $t_w = 10 \mu s$	_	220	_		
Total gate charg plus gate-drain)	e (Gate-source	^{Qg}		_	170	_		
Gate-source charge		Q _{gs}	$V_{DD} \approx 48 \text{ V}, V_{GS} = 10 \text{ V}, I_D = 60 \text{ A}$		110	_	nC	
Gate-drain ("miller") charge		Q _{gd}			60			

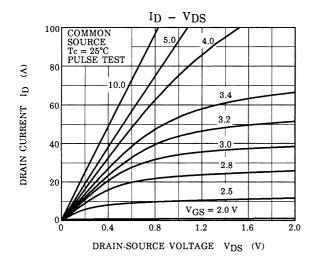
Source-Drain Ratings and Characteristics (Ta = 25°C)

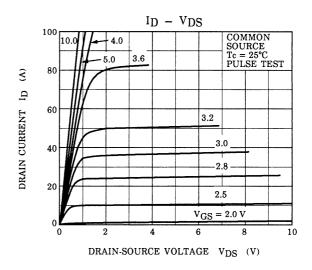
Characteristics	Symbol	Test Condition	Min	Тур.	Max	Unit
Continuous drain reverse current (Note 1)	I _{DR}	_	-	_	60	Α
Pulse drain reverse current (Note 1)	I _{DRP}	_	-	_	240	Α
Forward voltage (diode)	V _{DSF}	I _{DR} = 60 A, V _{GS} = 0 V	_	_	-1.7	V
Reverse recovery time	t _{rr}	I _{DR} = 60 A, V _{GS} = 0 V		150	_	ns
Reverse recovered charge	Q _{rr}	dl _{DR} / dt = 50 A / μs		0.3	_	μC

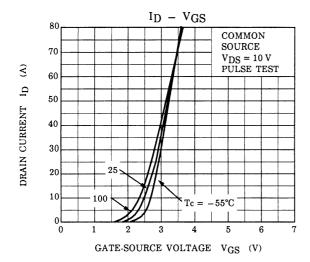
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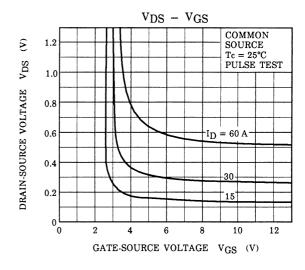


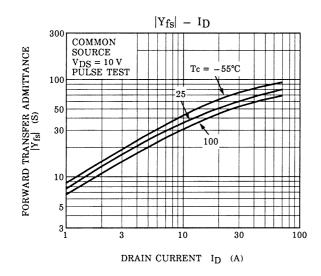
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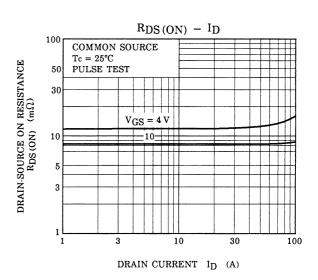




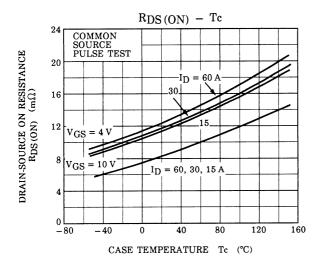


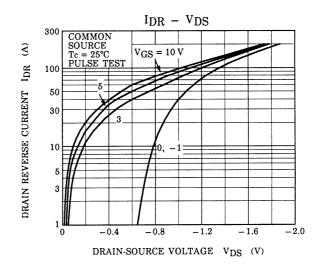


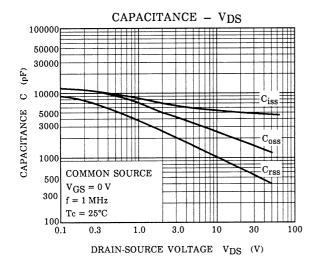


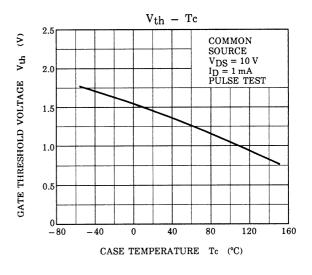


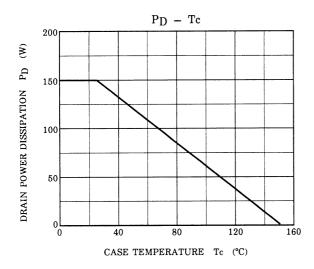
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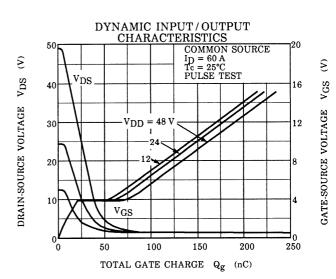




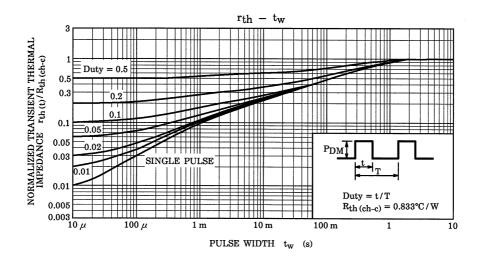


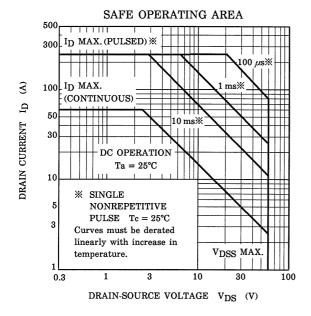


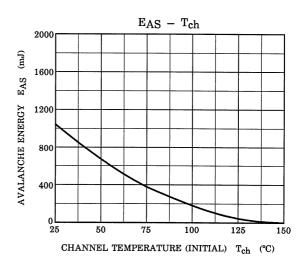


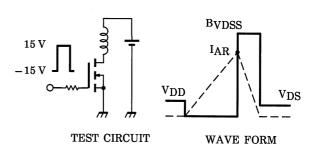


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$$\begin{aligned} &R_G = 25~\Omega \\ &V_{DD} = 25~V,~L = 398~\mu H \end{aligned} \qquad EAS = \frac{1}{2} \cdot L \cdot I^2 \cdot \left(\frac{BVDSS}{BVDSS - VDD} \right) \end{aligned}$$

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